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Term:

115 and (compress\$4 or compact\$4) same (pull\$1up
 or pull\$1down) same latch\$4 same (ic or (integrat\$3
 near2 circuit\$3) or semi\$1conduct\$7 or
 memor\$7) and (clock or timing) same (test\$3 or

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	DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
<u>L18</u>	115 and 116	4	<u>L18</u>
<u>L17</u>	115 and (compress\$4 or compact\$4) same (pull\$1up or pull\$1down) same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	4	<u>L17</u>
<u>L16</u>	114 and (compress\$4 or compact\$4) same (pull\$1up or pull\$1down) same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	4	<u>L16</u>
<u>L15</u>	114 and (compress\$4 or compact\$4) and (pull\$1up or pull\$1down) same latch\$4 same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4)	43	<u>L15</u>

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<u>L13</u>	(compress\$4 or compact\$4) and (pull\$1up or pull\$1down)same latch\$4	498	<u>L13</u>
<u>L12</u>	l1 and (pull\$1up or pull\$1down)same latch\$4	1	<u>L12</u>
<u>L11</u>	l7 and (pull\$1up or pull\$1down)same latch\$4	1	<u>L11</u>
<u>L10</u>	(pull\$1up or pull\$1down)same latch\$4	2589	<u>L10</u>
<u>L9</u>	('6163491')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L9</u>
<u>L8</u>	l7 and double data rate same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)	1	<u>L8</u>
<u>L7</u>	l6 and double data rate and (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7) and (clock or timing)	11	<u>L7</u>
<u>L6</u>	double data rate and (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	12	<u>L6</u>
<u>L5</u>	l1 and (double near (data or rate) or ddr)same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) and (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	11	<u>L5</u>
<u>L4</u>	('6324602')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L4</u>
<u>L3</u>	('6317372')[ABPN1,NRPN,PN,TBAN,WKU]	2	<u>L3</u>
<u>L2</u>	l1 and (double near (data or rate) or ddr)same (compress\$4 or compact\$4) same (test\$3 or debug\$4 or verif\$7 or diagno\$5 or probing or probe or exerci\$4) same (ic or (integrat\$3 near2 circuit\$3) or semi\$1conduct\$7 or memor\$7)	3	<u>L2</u>
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END OF SEARCH HISTORY